

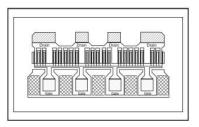
## FEATURES

- High Output Power: P<sub>1dB</sub> = 30.0dBm(Typ.)
- High Gain:  $G_{1dB} = 6.5 dB(Typ.)$
- High Power Added Efficiency: PAE = 31%(Typ.)
- Proven Reliability

### DESCRIPTION

The FLK107XV chip is a power GaAs FET that is designed for general purpose applications in the Ku-Band frequency range as it provides superior power, gain, and efficiency. Sumitomo Electric stringent Quality Assurance Program assures

the highest reliability and consistent performance.



SUMITOMO ELECTRIC

*FLK107XV* 

GaAs FET Chips

## ABSOLUTE MAXIMUM RATING (Ambient Temperature Ta=25deg.C)

Item	Symbol	Condition	Rating	Unit
Drain-Source Voltage	V <sub>DS</sub>		15	V
Gate-Source Voltage	V <sub>GS</sub>		-5	V
Total Power Dissipation	P <sub>tot</sub>	Tc = 25deg.C	7.50	W
Storage Temperature	T <sub>stg</sub>		-65 to +175	deg.C
Channel Temperature	T <sub>ch</sub>		175	deg.C

Sumitomo Electric recommends the following conditions for the reliable operation of GaAs FETs:

1. The drain-source operating voltage (V  $_{\mbox{\scriptsize DS}}$  ) should not exceed 10 volts.

2. The forw ard and reverse gate currents should not exceed 8.8 and -0.5 mA respectively with gate resistance of 500ohm.

3. The operating channel temperature (T<sub>ch</sub>) should not exceed 145deg.C.

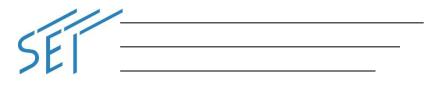
### ELECTRICAL CHARACTERISTICS (Ambient Temperature Ta=25deg.C)

Item	Symbol	Test Conditions	Limit			Unit	
nem	Symbol	Test conditions	Min.	Тур.	Max.	Unit	
Saturated Drain Current	I <sub>DSS</sub>	$V_{DS} = 5V, V_{GS} = 0V$	-	400	600	mA	
Transconductance	gm	$V_{DS} = 5V, I_{DS} = 250mA$	-	200	-	mS	
Pinch-off Voltage	Vp	$V_{DS} = 5V, I_{DS} = 20mA$	-1.0	-2.0	-3.5	V	
Gate Source Breakdown Voltage	V <sub>GSO</sub>	$I_{GS} = -20uA$	-5	-	-	V	
Output Power at 1dB Gain Compression Point	$P_{1dB}$	V <sub>DS</sub> = 10V	29	30	-	dBm	
Power Gain at 1dB Gain Compression Point	G <sub>1dB</sub>	l <sub>DS</sub> ≈ 0.6l <sub>DSS</sub> f = 14.5GHz	5.5	6.5	-	dB	
Power-added Efficiency	PAE	1 - 14.00112	-	31	-	%	
Thermal Resistance	R <sub>th</sub>	Channel to Case	-	15	20	deg.C/W	

Note: RF parameter sample size 10pcs. criteria (accept/reject)=(2/3)

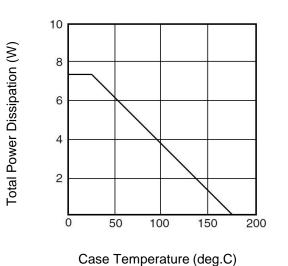
The chip must be enclosed in a hermetically sealed environment for optimum performance and reliability.

RoHS Compliance	Yes
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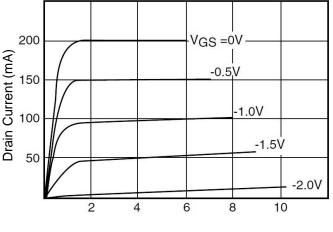


POWER DERATING CURVE

**FLK107XV** GaAs FET Chips

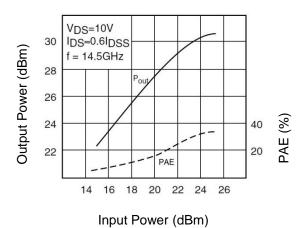


## DRAIN CURRENT vs. DRAIN-SOURCE VOLTAGE

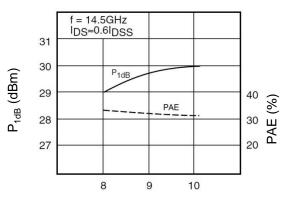


Drain-Source Voltage (V)

OUTPUT POWER vs. INPUT POWER

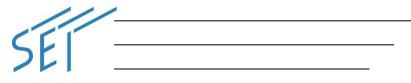


P<sub>1dB</sub> & PAE vs. V<sub>DS</sub>



Drain-Source Voltage (V)

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# **FLK107XV** GaAs FET Chips

## S-PARAMETERS

 $V_{DS} = 10V, I_{DS} = 240mA$ 

Freq	S1 <sup>-</sup>	1	• <sub>DS</sub> – S2 <sup>-</sup>	100, 1 <sub>DS</sub> –	24011A S12	2	S2:	2
(MHz)	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
100	0.998	-14.5	11.209	171.6	0.007	82.1	0.214	-15.0
500	0.972	-65.3	9.441	142.2	0.031	54.8	0.227	-64.9
1000	0.941	-105.2	6.826	118.3	0.045	33.6	0.246	-98.3
1500	0.926	-127.5	5.082	103.5	0.050	21.4	0.263	-113.5
2000	0.919	-141.3	3.976	93.0	0.052	13.5	0.282	-121.0
2500	0.915	-150.7	3.236	84.7	0.053	7.8	0.302	-125.1
3000	0.913	-157.5	2.713	77.6	0.053	3.3	0.324	-127.7
3500	0.913	-162.9	2.325	71.3	0.053	-0.4	0.346	-129.6
4000	0.912	-167.3	2.026	65.6	0.053	-3.6	0.370	-131.1
4500	0.913	-171.0	1.789	60.2	0.053	-6.4	0.394	-132.6
5000	0.913	-174.2	1.596	55.1	0.052	-8.9	0.418	-134.0
5500	0.914	-177.1	1.436	50.2	0.052	-11.3	0.441	-135.4
6000	0.915	-179.7	1.301	45.5	0.051	-13.5	0.465	-136.8
6500	0.916	177.9	1.186	41.0	0.051	-15.5	0.487	-138.3
7000	0.917	175.6	1.086	36.6	0.050	-17.4	0.509	-139.8
7500	0.918	173.5	1.000	32.3	0.050	-19.2	0.530	-141.2
8000	0.919	171.5	0.923	28.2	0.049	-20.9	0.551	-142.7
8500	0.920	169.6	0.856	24.2	0.048	-22.5	0.570	-144.2
9000	0.921	167.7	0.795	20.3	0.048	-24.0	0.589	-145.7
9500	0.923	165.9	0.741	16.5	0.047	-25.5	0.607	-147.2
10000	0.924	164.2	0.692	12.7	0.046	-26.8	0.624	-148.7
10500	0.925	162.5	0.648	9.1	0.046	-28.2	0.640	-150.1
11000	0.926	160.9	0.608	5.6	0.045	-29.4	0.655	-151.6
11500	0.927	159.3	0.572	2.1	0.044	-30.6	0.669	-153.0
12000	0.928	157.7	0.538	-1.2	0.044	-31.8	0.683	-154.4
12500	0.929	156.2	0.508	-4.5	0.043	-32.9	0.696	-155.8
13000	0.930	154.7	0.479	-7.8	0.042	-33.9	0.708	-157.1
13500	0.932	153.2	0.453	-10.9	0.042	-34.9	0.720	-158.5
14000	0.933	151.7	0.429	-14.0	0.041	-35.9	0.731	-159.8
14500	0.934	150.3	0.407	-17.0	0.040	-36.8	0.741	-161.1
15000	0.935	148.9	0.386	-19.9	0.040	-37.7	0.751	-162.3
15500	0.936	147.5	0.367	-22.8	0.039	-38.6	0.760	-163.6
16000	0.937	146.1	0.349	-25.6	0.039	-39.4	0.769	-164.8
16500	0.937	144.8	0.333	-28.4	0.038	-40.2	0.777	-166.0
17000	0.938	143.5	0.317	-31.1	0.038	-41.0	0.785	-167.1
17500	0.939	142.1	0.302	-33.7	0.037	-41.7	0.793	-168.3
18000	0.940	140.8	0.289	-36.3	0.037	-42.5	0.800	-169.4
18500	0.941	139.6	0.276	-38.8	0.036	-43.2	0.806	-170.5
19000	0.942	138.3	0.264	-41.3	0.036	-43.8	0.813	-171.6
19500	0.943	137.1	0.252	-43.8	0.035	-44.5	0.819	-172.7
20000	0.944	135.8	0.241	-46.2	0.035	-45.1	0.824	-173.8

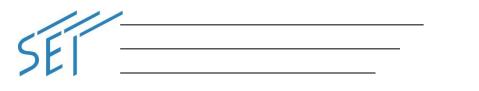
NOTE:\* The data includes bonding wires.

n: number of wires Gate

Drain

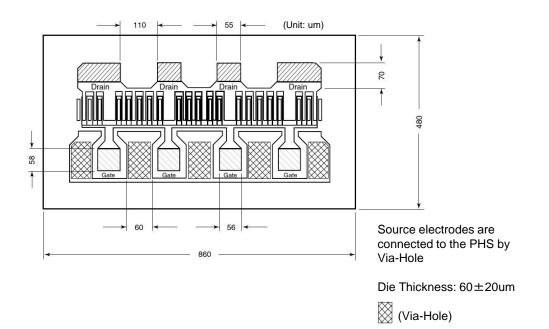
n=4 (0.2mm length, 25um Dia Au wire) n=4 (0.2mm length, 25um Dia Au wire)

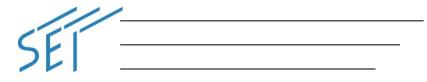




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## CHIP OUTLINE





#### BARE DIE INDEMNIFICATION

All devices are DC probed and visually inspected at SEI, and non-compliant devices are removed. The RF electrical characteristics of the bare dice are warranted by the sampling inspection procedures. The standard sampling inspection procedure shall include the number of the sampling dice, position of the sampling dice in the wafer and RF electrical characteristics of the sampling dice measured in the test fixture. Customer shall understand that all the bare dice will not be 100% RF tested by SEI. It is the customer responsibility to verify performance of the devices.

Customer shall comply with the storage and handling requirements for condition and period of storage of the bare dice agreed by customer and SEI. Warranty will not apply when customer disregards the storage and handling requirements.

Warranty will not apply to the electrical characteristics and product quality to the bare dice after assembly by customer.

SEI will indemnify customer for warranty failures, provided however that the indemnification to customer shall be limited to supply of bare dice for substitution.

### CAUTION

Sumitomo Electric Device Innovations, Inc. products contain **gallium arsenide (GaAs)** which can be hazardous to the human body and the environment. For safety, observe the following procedures:

• Do not put these products into the mouth.

• Do not alter the form of this product into a gas, powder, or liquid through burning, crushing, or chemical processing as these by-products are dangerous to the human body if inhaled, ingested, or swallowed.

•Observe government laws and company regulations when discarding this product. This product must be discarded in accordance with methods specified by applicable hazardous waste procedures.

